

<p style="text-align: center;">Search Notes</p> 	<p>Application/Control No.</p> <p>10/520,169</p> <p>Examiner</p> <p>Shin-Lin Chen</p>	<p>Applicant(s)/Patent under Reexamination</p> <p>BACON ET AL.</p> <p>Art Unit</p> <p>1632</p>	
SEARCHED		SEARCH NOTES (INCLUDING SEARCH STRATEGY)	
Class	Subclass	Date	Examiner
424	184.1	5/28/2009	SLC
435	320.1		
	455	5/28/2009	SLC
530	350	5/28/2009	SLC
536	23.5	5/28/2009	SLC
INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
424	184.1	5/28/2009	SLC
435	320.1		
	455	5/28/2009	SLC
530/350, 536/23.5, AU interference search		5/28/2009	SLC